- Member of Texas Instruments' Widebus™ **Family**
- Bus Hold on Data Inputs Eliminates the **Need for External Pullup/Pulldown** Resistors
- Latch-Up Performance Exceeds 250 mA Per **JESD 17**
- **ESD Protection Exceeds JESD 22**
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)

description

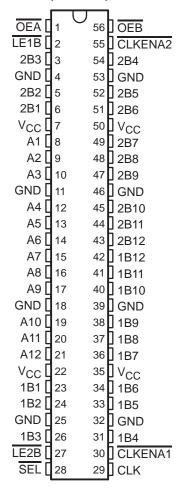
This 12-bit to 24-bit bus exchanger is designed for 1.65-V to 3.6-V V_{CC} operation.

SN74ALVCH16271 is intended applications in which two separate data paths must be multiplexed onto, or demultiplexed from, a single data path. This device is particularly suitable as an interface between conventional DRAMs and high-speed microprocessors.

A data is stored in the internal A-to-B registers on the low-to-high transition of the clock (CLK) input, provided that the clock-enable (CLKENA) inputs are low. Proper control of these inputs allows two sequential 12-bit words to be presented as a 24-bit word on the B port.

Transparent latches in the B-to-A path allow asynchronous operation to maximize memory access throughput. These latches transfer data when the latch-enable (\overline{LE}) inputs are low. The select (SEL) line selects 1B or 2B data for the A outputs. Data flow is controlled by the active-low output enables (OEA, OEB).

DGG OR DL PACKAGE (TOP VIEW)



To ensure the high-impedance state during power up or power down, the output enables should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry holds unused or undriven inputs at a valid logic state. Use of pullup or pulldown resistors with the bus-hold circuitry is not recommended.



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Widebus is a trademark of Texas Instruments.



ORDERING INFORMATION

TA	PACKAGE [†]		ORDERABLE PART NUMBER	TOP-SIDE MARKING	
-40°C to 85°C	SSOP – DL	Tube	SN74ALVCH16271DL	ALVCH16271	
	330F - DL	Tape and reel	SN74ALVCH16271DLR	ALVCH102/1	
	TSSOP – DGG	Tape and reel	SN74ALVCH16271DGGR	ALVCH16271	

[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

Function Tables

OUTPUT ENABLE

INP	UTS	OUTPUTS			
OEA	OEB	Α	1B, 2B		
Н	Н	Z	Z		
Н	L	Z	Active		
L	Н	Active	Z		
L	L	Active	Active		

A-TO-B STORAGE ($\overline{OEB} = L$)

	OUTPUTS				
CLKENA1	CLKENA2	CLK	Α	1B	2B
Н	Н	Х	Χ	1B ₀ ‡	2B ₀ ‡
L	Χ	\uparrow	L	L	Х
L	Χ	\uparrow	Н	Н	Х
Х	L	\uparrow	L	Х	L
Х	L	\uparrow	Н	A ₀	Н

[‡]Output level before the indicated steady-state input conditions were established

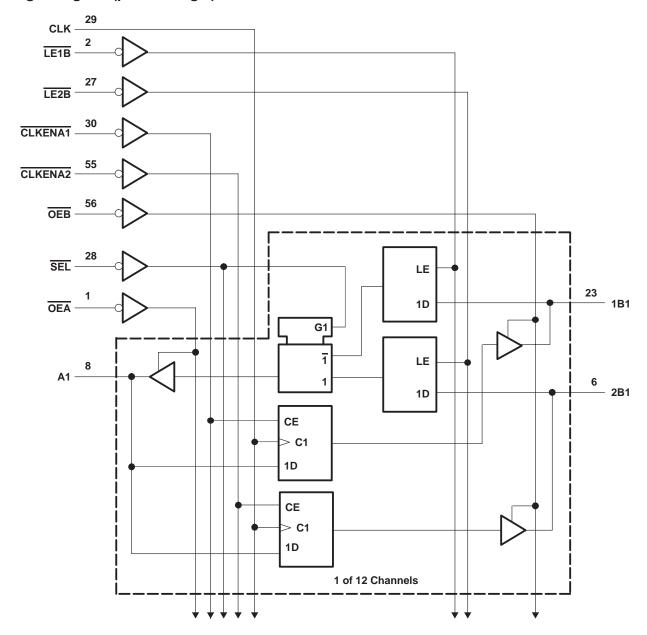
B-TO-A STORAGE ($\overline{OEA} = L$)

	INP	INPUTS		
LE	SEL	1B	2B	Α
Н	Х	Х	Х	A ₀ ‡
Н	Χ	Χ	X	A ₀ ‡ A ₀ ‡
L	Н	L	X	L
L	Н	Н	X	Н
L	L	Χ	L	L
L	L	Χ	Н	Н

[‡] Output level before the indicated steady-state input conditions were established



logic diagram (positive logic)





SN74ALVCH16271 12-BIT TO 24-BIT MULTIPLEXED BUS EXCHANGER WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V _{CC}	
Input voltage range, V _I : Except I/O ports (see Note 1)	
I/O ports (see Notes 1 and 2)	
Output voltage range, VO (see Notes 1 and 2)	
Input clamp current, I _{IK} (V _I < 0)	
Output clamp current, I _{OK} (V _O < 0)	
Continuous output current, IO	±50 mA
Continuous current through each V _{CC} or GND	±100 mA
Package thermal impedance, θ _{JA} (see Note 3): DGG package	64°C/W
DL package	56°C/W
Storage temperature range, T _{sta}	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. This value is limited to 4.6 V maximum.
 - 3. The package thermal impedance is calculated in accordance with JESD 51-7.

recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
Vcc	Supply voltage		1.65	3.6	V
		V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}		
V_{IH}	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7		V
	V _{IH} High-level input voltage V _{IL} Low-level input voltage V _I Input voltage	$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2		
		V _{CC} = 1.65 V to 1.95 V		0.35 × V _{CC}	
V_{IL}	Low-level input voltage	V _{CC} = 2.3 V to 2.7 V		0.7	V
		V _{CC} = 2.7 V to 3.6 V		0.8	
٧ı	Input voltage	<u> </u>	0	VCC	V
٧o	Output voltage		0	VCC	V
		V _{CC} = 1.65 V		-4	
		V _{CC} = 2.3 V		-12	^
ЮН	High-level output current	V _{CC} = 2.7 V		-12	mA
		V _{CC} = 3 V	5 V 0.65 × V _{CC} 1.7 2 5 V 0.35 × V _{CC} 0.7 0.8 0 V _{CC} 0 V _{CC} -4 -12		
		V _{CC} = 1.65 V		4	
1	Laurence autorit aumant	V _{CC} = 2.3 V		12	^
IOL	Low-level output current	V _{CC} = 2.7 V		12	mA
		VCC = 3 V		24	
Δt/Δν	Input transition rise or fall rate	•		10	ns/V
TA	Operating free-air temperature		-40	85	°C

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PAI	RAMETER	TEST CONDITIONS	Vcc	MIN	TYP†	MAX	UNIT
		$I_{OH} = -100 \mu\text{A}$	1.65 V to 3.6 V	V _{CC} -0.2			
		$I_{OH} = -4 \text{ mA}$	1.65 V	1.2			
VOL II IOZ ICC AICC		$I_{OH} = -6 \text{ mA}$	2.3 V	2			
VOH			2.3 V	1.7		0.2 0.45 0.4 0.7 0.4 0.55 ±5 10 40 750	V
		$I_{OH} = -12 \text{ mA}$	2.7 V	2.2			
			3 V	2.4			
I _{OH} = -24 mA			3 V	2			
		I _{OL} = 100 μA	1.65 V to 3.6 V			0.2	
		I _{OL} = 4 mA	1.65 V			0.45	
V		I _{OL} = 6 mA	2.3 V			0.4	V
VOL		1- 40 mA	2.3 V			0.7	V
		I _{OL} = 12 mA	2.7 V			0.4	
		I _{OL} = 24 mA	3 V			0.55	
II		V _I = V _{CC} or GND	3.6 V			±5	μΑ
		V _I = 0.58 V	1.65 V	25			
		V _I = 1.07 V	1.65 V	-25			
		V _I = 0.7 V	2.3 V	45			
I _{I(hold)}	1	V _I = 1.7 V	2.3 V	-45			μΑ
		V _I = 0.8 V	3 V	75			
		V _I = 2 V	3 V	-75			
		V _I = 0 to 3.6 V [‡]	3.6 V			±500	
loz§		$V_O = V_{CC}$ or GND	3.6 V			±10	μΑ
		$V_I = V_{CC}$ or GND, $I_O = 0$	3.6 V			40	μΑ
Δlcc		One input at V _{CC} – 0.6 V, Other inputs at V _{CC} or GND	3 V to 3.6 V			750	μΑ
Ci	Control inputs	V _I = V _{CC} or GND	3.3 V		3.5		рF
Cio	A or B ports	$V_O = V_{CC}$ or GND	3.3 V		9		pF

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} =		V _{CC} =	2.7 V	V _{CC} =	V _{CC} = 3.3 V ± 0.3 V	
			MIN	MAX	MIN	MAX	MIN	MAX	
fclock	Clock frequency			130		130		130	MHz
t _W	Pulse duration, CLK high or low		3.3		3.3		3.3		ns
	Setup time	A before CLK↑	2.6		2.1		1.7		
t _{su}		B before LE	1.7		1.5		1.3		ns
		CLKEN before CLK↑	1.6		1.3		1	MAX	
		A after CLK↑	0.6		0.6		0.7		
th	Hold time	B after LE	0.9		0.9		1.1		ns
		CLKEN after CLK↑	1		0.9		0.9		



[†] All typical values are at V_{CC} = 3.3 V, T_A = 25°C. ‡ This is the bus-hold maximum dynamic current. It is the minimum overdrive current required to switch the input from one state to another.

 $[\]mbox{\ensuremath{\,\$}}$ For I/O ports, the parameter IOZ includes the input leakage current.

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

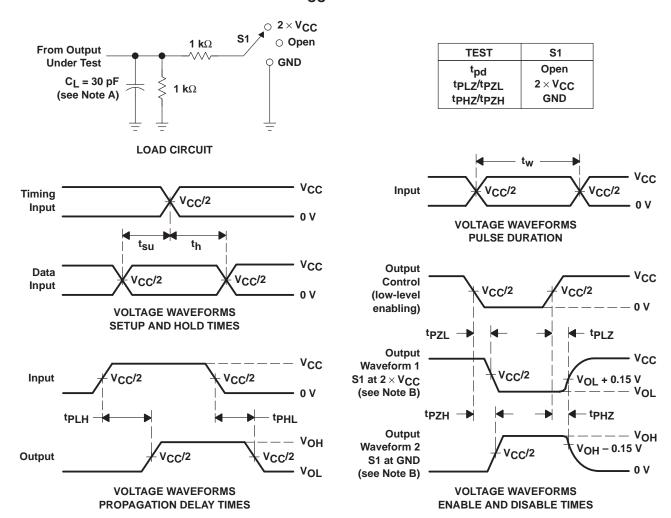
PARAMETER	FROM TO (INPUT) (OUTPUT)		V _{CC} = 1.8 V	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
	(INFOT)	(0011 01)	TYP	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}				130		130		130		MHz
	CLK	В	8	1	6.2		5	1	4.3	
	В		7	1	5.3		4.7	1.4	4	ne
^t pd	LE	Α	7	1	6		5.9	1.4	4.8	ns
	SEL		7	1.1	6.4		6.2	1.3	5.2	
t _{en}	OEB or OEA	B or A	8	1	6		6.1	1	5.1	ns
^t dis	OEB or OEA	B or A	7	1.4	5.4		4.6	1.7	4.2	ns

operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER				ONDITIONS	V _{CC} = 2.5 V	V _{CC} = 3.3 V	UNIT
PARAMETER			TEST CONDITIONS		TYP	TYP	UNIT	
C _{pd}		A to B	Outputs enabled	C _L = 0,		92	105	
	Down discinction consistence	AIUB	Outputs disabled		f = 10 MHz	61	76	~F
	Power dissipation capacitance	B to A	Outputs enabled			39	43	pF
			Outputs disabled			11	13	



PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8 \text{ V}$

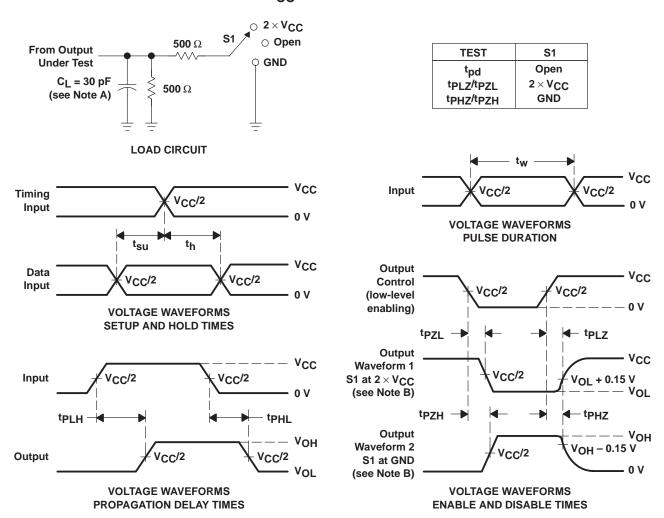


NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \ \Omega$, $t_f \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$



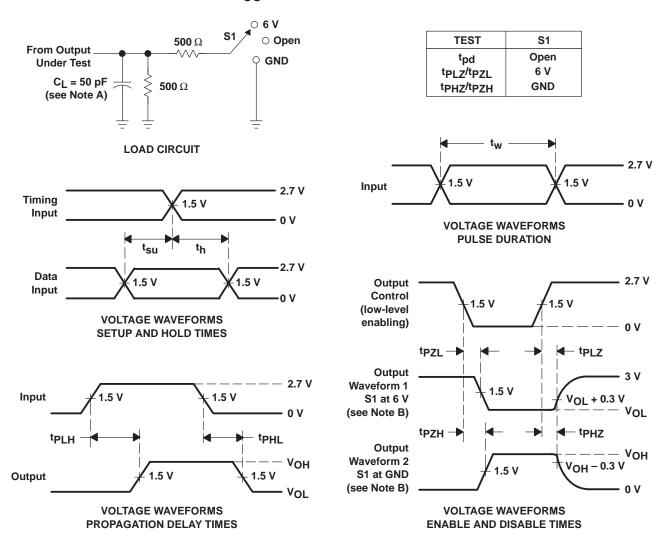
NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_Q = 50~\Omega$, $t_f \leq$ 2 ns, $t_f \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLZ and tpHZ are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION V_{CC} = 2.7 V AND 3.3 V \pm 0.3 V



- NOTES: A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_Q = 50 \Omega$, $t_f \leq 2.5$ ns. $t_f \leq 2.5$ ns.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. tpLZ and tpHZ are the same as tdis.
 - F. tpzL and tpzH are the same as ten.
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 3. Load Circuit and Voltage Waveforms

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Mailing Address:

Texas Instruments Post Office Box 655303 Dallas, Texas 75265